

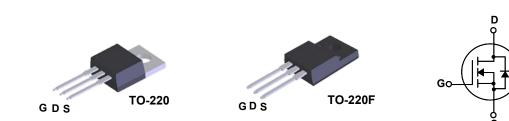
FQP9N25C / FQPF9N25C N-Channel QFET[®] MOSFET 250 V, 8.8 A, 430 mΩ

Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor®'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

Features

- + 8.8 A, 250 V, $R_{DS(on)}$ =430 m Ω (Max.)@V_{GS}=10 V, I_D=4.4 A
- Low Gate Charge (Typ. 26.5 nC)
- Low C_{rss} (Typ. 45.5 pF)
- 100% Avalanche Tested



Absolute Maximum Ratings T_c = 25°C unless otherwise noted

Parameter		FQP9N25C	FQPF9N25C	Unit
Drain-Source Voltage		2	V	
Drain Current - Continuous ($T_C = 25^{\circ}C$)		8.8	8.8 *	А
- Continuous (T _C = 100°C)		5.6	5.6 *	А
Drain Current - Pulsed	(Note 1)	35.2	35.2 *	Α
Gate-Source Voltage		± 30		V
Single Pulsed Avalanche Energy	(Note 2)	285		mJ
Avalanche Current	(Note 1)	8.8		А
Repetitive Avalanche Energy	(Note 1)	7.4		mJ
Peak Diode Recovery dv/dt (Note 3)		5.5		V/ns
Power Dissipation ($T_C = 25^{\circ}C$)		74	38	W
- Derate above 25°C		0.59	0.3	W/°C
Operating and Storage Temperature Range		-55 to +150		°C
Maximum lead temperature for soldering purposes,		300		°C
1/8" from case for 5 seconds				
	Orain Current- Continuous $(T_C = 25^\circ C)$ - Continuous $(T_C = 100^\circ C)$ Drain Current- PulsedGate-Source VoltageSingle Pulsed Avalanche EnergyAvalanche CurrentRepetitive Avalanche EnergyPeak Diode Recovery dv/dtPower Dissipation $(T_C = 25^\circ C)$ - Derate above $25^\circ C$ Operating and Storage Temperature RangeMaximum lead temperature for soldering purpose	Drain Current- Continuous ($T_C = 25^{\circ}C$) - Continuous ($T_C = 100^{\circ}C$)Drain Current- Pulsed(Note 1)Gate-Source VoltageSingle Pulsed Avalanche Energy(Note 2)Avalanche Current(Note 1)Repetitive Avalanche Energy(Note 1)Peak Diode Recovery dv/dt(Note 3)Power Dissipation ($T_C = 25^{\circ}C$) - Derate above $25^{\circ}C$ Operating and Storage Temperature RangeMaximum lead temperature for soldering purposes, $1/8^{\circ}$ from case for 5 seconds	Drain Current- Continuous ($T_C = 25^{\circ}C$) - Continuous ($T_C = 100^{\circ}C$)8.8 5.6Drain Current- Pulsed(Note 1)35.2Gate-Source Voltage \pm Single Pulsed Avalanche Energy(Note 2)2Avalanche Current(Note 1)8Repetitive Avalanche Energy(Note 1)7Peak Diode Recovery dv/dt(Note 3)5Power Dissipation ($T_C = 25^{\circ}C$) - Derate above $25^{\circ}C$ 74Operating and Storage Temperature Range-55 to1/8" from case for 5 seconds3	$\begin{array}{c c c c c c c c c } \hline \begin{tabular}{ c c c c c c c } \hline \begin{tabular}{ c c c c c c c c c c c c c c c c c c c$

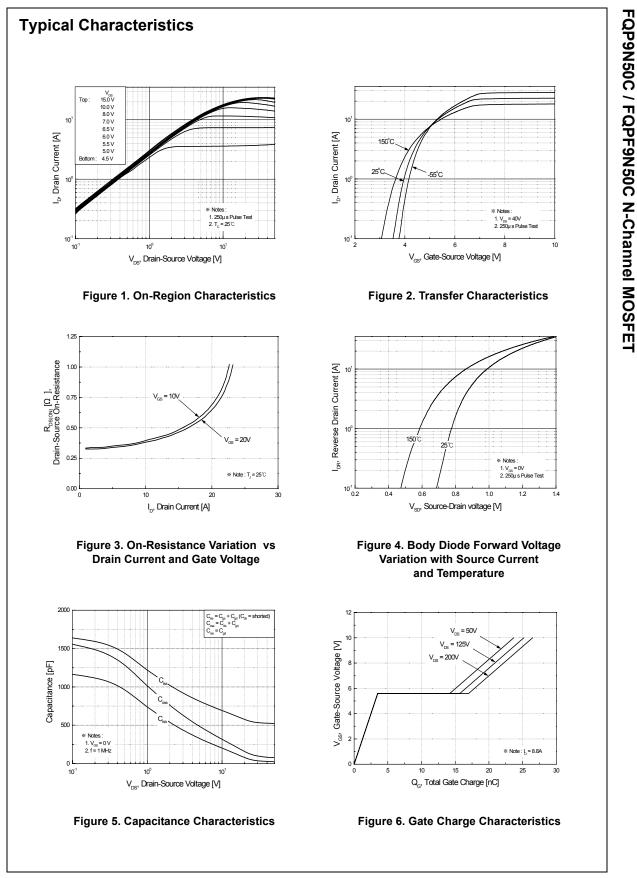
Thermal Characteristics

Symbol	Parameter	FQP9N25C	FQPF9N25C	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.69	3.29	°C/W
$R_{\theta JS}$	Thermal Resistance, Case-to-Sink Typ.	0.5		°C/W
R _{0JA} Thermal Resistance, Junction-to-Ambient		62.5	62.5	°C/W

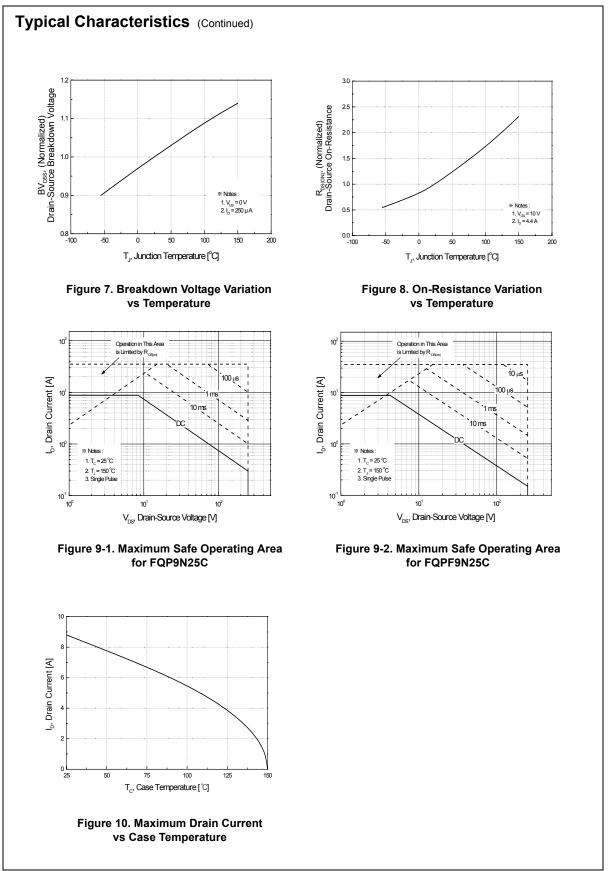
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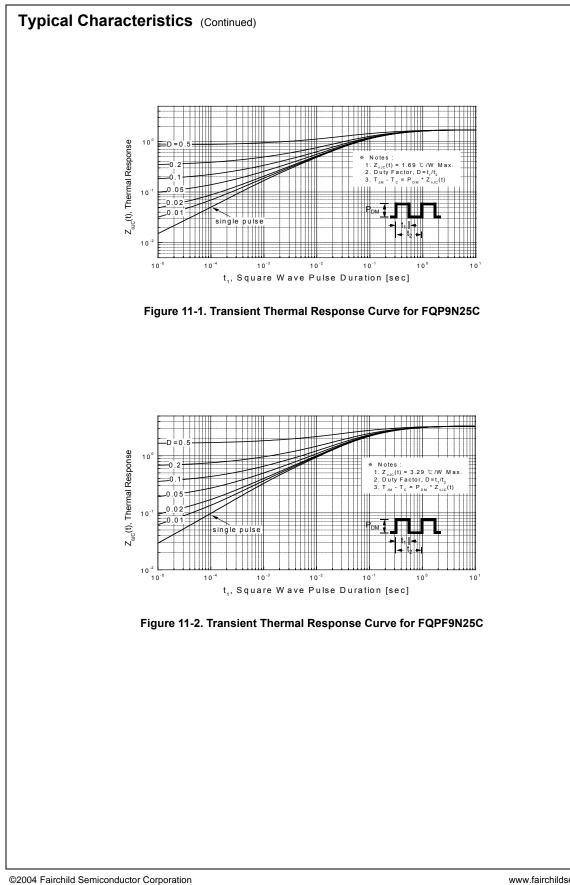
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	racteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	250			V
ΔBV _{DSS}	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu$ A, Referenced to 25°C		0.30		V/°C
DSS	Zero Gate Voltage Drain Current	$V_{DS} = 250 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 200 \text{ V}, T_{C} = 125^{\circ}\text{C}$			10 100	μA μA
GSSF	Gate-Body Leakage Current, Forward	$V_{GS} = 30 V, V_{DS} = 0 V$			100	nA
GSSR	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$			-100	nA
	racteristics				I	
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250 μA	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 4.4 \text{ A}$		0.35	0.43	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 40 \text{ V}, \text{ I}_{D} = 4.4 \text{ A}$ (Note 4)		7.0		S
Dynami	in Characteristics	1			I	
S _{iss}	ic Characteristics	<u> </u>		545	710	pF
C _{oss}	Output Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		115	150	pF
C _{rss}	Reverse Transfer Capacitance			45.5	60	pF
d(on)	ng Characteristics Turn-On Delay Time Turn-On Rise Time	$V_{DD} = 125 \text{ V}, \text{ I}_{D} = 8.8 \text{ A},$		15 85	40 180	ns
r	Turn-On Rise Time	$V_{DD} = 125 \text{ V}, \text{ I}_{D} = 8.8 \text{ A},$ R _G = 25 Ω		85	180	ns
d(off)	Turn-Off Delay Time			90	190	ns
f	Turn-Off Fall Time	(Note 4, 5)		65	140	ns
ට _g	Total Gate Charge	V _{DS} = 200 V, I _D = 8.8 A,		26.5	35	nC
ୁ _{gs}	Gate-Source Charge	V _{GS} = 10 V		3.5		nC
ପୁ _{gd}	Gate-Drain Charge	(Note 4, 5)		13.5		nC
Drain-S	ource Diode Characteristics a	nd Maximum Ratings				
s	Maximum Continuous Drain-Source Diode Forward Current				8.8	Α
SM	Maximum Pulsed Drain-Source Diode F				35.2	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 8.8 A			1.5	V
'n	Reverse Recovery Time	V _{GS} = 0 V, I _S = 8.8 A,		218		ns
ל ^{ער}	Reverse Recovery Charge	$dI_{F} / dt = 100 \text{ A}/\mu \text{s}$ (Note 4)		1.58		μC
L = 5.9mH, I I _{SD} ≤ 8.8A, c Pulse Test :	ating : Pulse width limited by maximum junction tempe $_{AS}$ = 8.8A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C fi/dt \leq 300A/µs, V_{DD} \leq BV $_{DSS}$ Starting T_J = 25°C Pulse width \leq 300µs, Duty cycle \leq 2% dependent of operating temperature	rature				



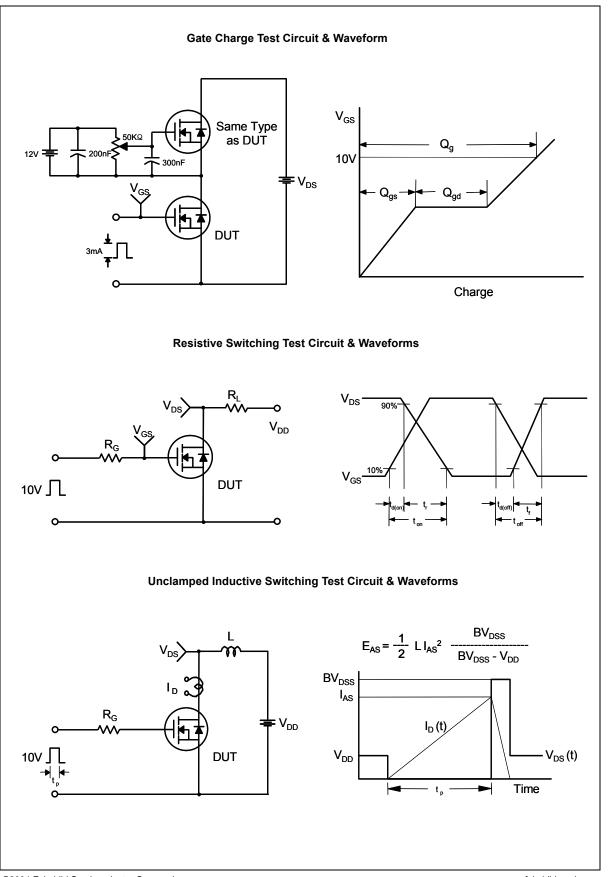
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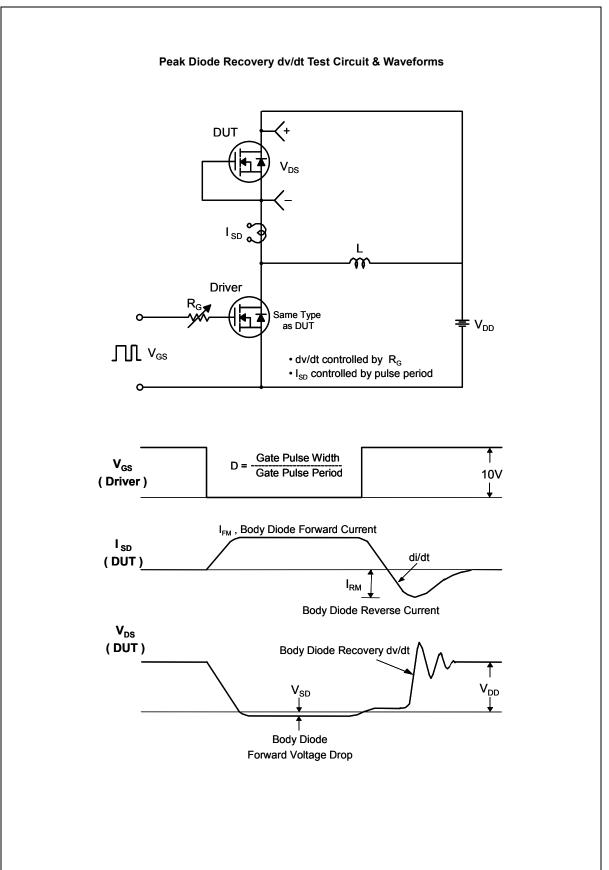
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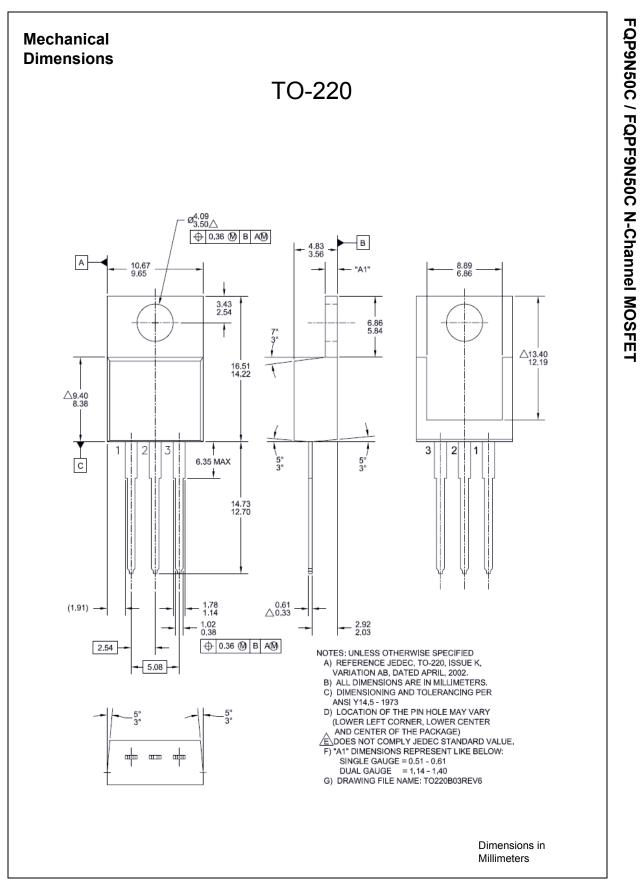


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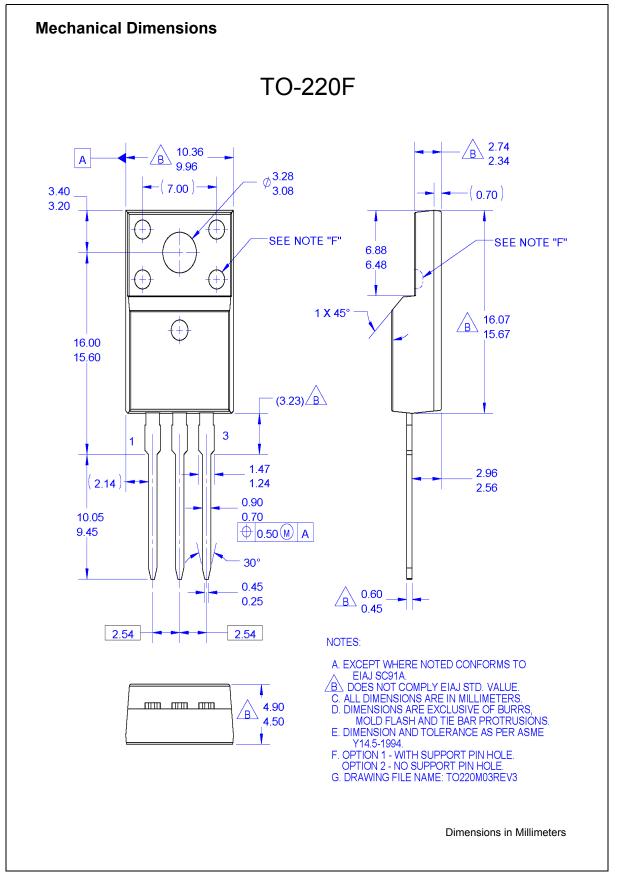
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